

Quantum Emission from Hexagonal Boron Nitride

A thesis submitted for the degree of Doctor of Philosophy at

University of Technology Sydney

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April 2018

Certificate of Original Authorship

I, Trong Toan Tran, certify that the work in this dissertation entitled, "Quantum emission from Hexagonal Boron Nitride", has not previously been submitted for a degree nor has it been submitted as part of requirements for a degree except as fully acknowledged within the text.

I also attest that the dissertation has been written by myself. Any help that I have received in my research work and the preparation of the dissertation itself has duly been acknowledged. In addition, I certify that all information sources and literature used are indicated in the dissertation.

This research is supported by an Australian Government Research Training Program Scholarship.

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Date: 23 March 2018

To my loved ones

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Acknowledgements

My doctorate journey would not have been made possible without the help of people mentioned in this acknowledgement section. First, I would like to express my utmost gratitude to my supervisors: Professor Igor Aharonovich, Prof. Milos Toth, and Associate Professor Charlene Lobo.

It has been my great honor to have an opportunity to work with Prof. Milos Toth whose knowledge in physics is unparalleled. He has taught me, a researcher majoring in materials sciences and chemical engineering, the physics of all kinds, from classical to quantum regime. More importantly, he patiently steps me through physical concepts that are very arduous to grasp. Outside working environment, he is a kind-hearted gentleman that mentally supports me significantly when I encounter social challenges in my early days in Australia. While I learn a great deal of physics from Prof. Toth, Prof. Aharonovich, on the other hand, has been showing me not only in-depth knowledge but also hands-on experience in quantum optics and photonics. Prof. Aharonovich is a lovely and dedicated advisor. He tirelessly guides me through individual equations and concepts in quantum optics and nanophotonics until I can completely understand those. He also gives me a plenty of opportunities to get to know experts in the field, network and collaborate with them. Thanks to these occasions, I have greatly improved my collaborative skills and become a more professional team player. I also want to extend my gratitude to Professor Lobo. She has dramatically helped me not only with technical problems but also with administrative matters.

My gratitude also goes to my thesis examiners, Assoc. Prof. Nick Vamivakas (University of Rochester), and Assoc. Prof. Paul Barclay (University of Calgary), for their time and effort spent on examining my thesis. Their comments and feedbacks help make my thesis better.

I would also like to thank other academic staff – Dr. Olga Shimoni, Dr. Jinghua Fang, Dr. Zai-quan (Sean) Xu, Dr. Sejeong Kim, Dr. Carlo Bradac, Dr. Angus Gentle and Dr. Gediminas Seniutinas – who get involved in my research, help me out with fruitful suggestions and share their invaluable experience. Without these dedicated staff, I could not have been able to finish the projects promptly.

The technical staff – Mr. Geoff McCredie, Ms. Katie McBean, Mr. Mark Berkahn and Mr, Herbert Yuan – also play a critical role in my Ph.D. journey. They have been maintaining, troubleshooting and upgrading to keep the facilities at their top performance; and they are very amiable, helpful and dedicated to all the students and staff in the Microstructure Analysis Unit (MAU). My gratitude also goes to the team in the mechanical workshop who help fabricate scientific tools that are invaluable to my experiments.

My academic journey would have missed most of its meaning without having the fellow students in MAU. They not only guide me through technical problems but also have become my companions in and outside the lab. I could still remember the daily morning coffee session and lunch break where we usually not only deepen our discussion into a specific scientific topic but also extend our arguments to general science. These moments will probably be with me for years down the road. I would, therefore, like to thank Mehran Kianinia, Amanuel Berhane, Kerem Bray, Russell Sandstrom, John Scott, Mika Tham Gleeson, Chris Elbadawi, James Bishop, Cameron Zachreson, Sumin Choi, Vikram Nikam, Daniel Totonjian, Minh Nguyen, Hanh Duong and Blake Reagan.

It has been my great pleasure to work with our collaborators from institutions around the globe: Prof. Dirk Englund, Dr. Gabriele Grosso, Tim Schroder, Dr. Hyowon Moon, and Mr. Benjamin Lienhard from Massachusetts Institute of Technology (MIT) for the work on quantum emitters in hexagonal boron nitride and silicon carbide; Prof. Michael Fuhrer and Dr. Changxi Zheng from Monash University, and Dr. Avi Bendavid from CSIRO for the study on single photon emitters in oxidized tungsten diselenide; Dr. Andrea Schell, Prof. Shigeki Takeuchi and Dr. Hideaki Takashima for the investigation on non-linear optics and coupling to taper fiber of hBN quantum emitters; Prof. Teri Odom, Danqing Wang, and Ankun Yang for the work on hBN emitter - plasmonic lattice coupling; Prof. Alexander Kubanek for the investigation on resonant excitation of quantum emitters from hBN; Dr. Jingjie Zhang from ANSTO for the work on synthesis and optical properties of nuclear-related compounds.

No research could have been carried out without sufficient fundings. I, therefore, would like to extend my gratitude towards the Australian Research Council (ARC) and FEI company for their financial support to my Ph.D. candidature. I also want to thank the Research Training Program (RTP) scheme from the Department of Education and Training for funding my stipend in part.

Lastly, I want to thank my wife, Thao, my daughter, Sophia, my parents and my extended family for their endless support and understanding during my Ph.D. journey. They are the most important people in my life. They have always been with me during good times as well as hardships. Without them, I would not have been able to finish this challenging academic adventure.

List of Publications

Refereed journal publications

 Tran, T. T.; Fang, J.; Zhang, H.; Rath, P.; Bray, K.; Sandstrom, R. G.; Shimoni,
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3) **Tran, T. T.**; Elbadawi, C.; Totonjian, D.; Lobo, C. J.; Grosso, G.; Moon, H.; Englund, D. R.; Ford, M. J.; Aharonovich, I.; Toth, M. "Robust Multicolor Single Photon Emission from Point Defects in Hexagonal Boron Nitride." *ACS Nano* 2016, 10, 7331-7338.

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Conference oral presentations

Tran T. T. et. al., "Quantum Emission from Hexagonal Boron Nitride Monolayers", International Conference of Nanoscience and Nanotechnology (ICONN), 2016, Canberra, Australia.

Tran T. T. et. al., "Quantum Emission from Hexagonal Boron Nitride Monolayers", 5th International Symposium on Graphene Devices (ISGD-5), 2016, Brisbane, Australia.

Tran T. T. et. al., "Quantum Emission from Hexagonal Boron Nitride", Conference on Optoelectronic and Microelectronic Materials and Devices (COMMAD), 2016, Sydney, Australia.

Tran T. T. et. al., "Quantum Emission from Hexagonal Boron Nitride", Conference on Lasers and Electro-Optics (CLEO), 2017, San Jose, USA.

Patents

Bishop, J.; **Tran, T. T.**; Aharonovich, I.; Lobo, C.; Toth, M. "Nanofabrication Using a New Class of Electron Beam Induced Surface Processing Techniques." US Patent: 2017; p US20170073814 A20170073811.

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Figure 3.5. Emitter creation and destruction upon sequential annealing at 500°C for 30 min each in H_2 , O_2 and NH_3 environments. The sample was first annealed in Ar at 850°C to generate emitters, and the black spectra in (a-c) were acquired from three different sample regions. (a) The green spectrum was acquired after annealing in H_2 from the same region as the black spectrum, and shows the disappearance of a number of emission lines (indicated by red arrows). (b) The red spectrum was acquired after the final annealing step in NH_3 from the same region as the black spectra were acquired after annealing in H_2 and O_2 , respectively, and show the appearance and disappearance of a number of emission lines. We note that no systematic trends were observed as a function of gas species. Instead, annealing in all three reactive environments caused the generated than destroyed after each annealing step. This behavior is expected based on the Ar annealing data shown in **Fig. 3.1(b)** of

the main paper. The quenching of some of the emitters is also not surprising. It merely indicates that some of the emitters are unstable, possibly because they are located in the topmost monolayers or edges of hBN flakes and hence sensitive to the annealing treatments.

Figure 3.6. Multicolor photoluminescence from point defects in hBN. (a) Simplified schematic of the photoluminescence setup showing the excitation and emission of a defect center in an hBN lattice. The objective lens, dichroic mirror, excitation source, and emission are denoted by Obj., DM, Exc., and Emi., respectively. (b) Five examples of emitters in Group 1 with ZPLs at 576 nm (2.15 eV), 583 nm (2.13 eV), 602 nm (2.06 eV), 633 nm (1.96 eV), and 652 nm (1.90 eV). (c) Four examples of emitters in Group 2 with ZPLs at 681 nm (1.82 eV), 696 nm (1.78 eV), 714 nm (1.74 eV), and 762 nm (1.63 eV). (d) Histogram of ZPL energy for numerous emitters in group 1 (red) and group 2 (blue). Each spectrum was acquired from a separate sample region at room temperature using a $300\mu W CW$ 532 nm laser. (e) Second-order autocorrelation functions showing that $g^{(2)}(0) =$ 0.39 and 0.34, respectively. The $g^{(2)}(\tau)$ functions were acquired using an excitation power of 300 μ W, an acquisition time of 20 sec, and were normalized (without background correction) and offset vertically for clarity. A neutral density filter was used to attenuate the signal generated by the 633 nm emitter. (f) Difference in the energy of the ZPL and PSB versus ZPL energy. The shaded band in (f) is a guide to the eye. In (b) and (c), high energy portions of some spectra were cut from the graph for clarity, to avoid overlaps between the spectra.

Figure 3.7. Photophysical properties of the defects. **(a)** Time-resolved fluorescence measurements showing radiative transition lifetimes of the emitters. An 80 μ W, 510 nm pulsed laser with a repetition rate of 20 MHz and a pulse width of 100 ps was used as the excitation source. The solid lines are fits obtained using single exponential decay functions. **(b)** Fluorescence saturation curves and corresponding theoretical fits calculated using a three-level model. **(c, d)** Second-

order autocorrelation function, $g^{(2)}(\tau)$, recorded over a longer time scale from the two color centers presented in **Fig. 3.6** with ZPLs at 633 (c) nm and 714 nm (d). The corresponding solid traces are theoretical fits to the experimental data. Insets show the fitting residue χ^2 versus the number of exponentials used in the fitting functions. The yellow bands indicate optimal fits realized when the number of exponentials and the residues are simultaneously minimized.

Figure 3.8. Short timescale second-order autocorrelation function, $g^{(2)}(\tau)$, obtained versus excitation power from the two color centers shown in **Fig. 3.6(e)** of the main text with ZPLs at **(a)** 633 nm, and **(b)** 714 nm. The $g^{(2)}(\tau)$ functions were acquired using a CW 532 nm laser, an acquisition time of 30 sec, and were normalized (without background correction) and offset vertically by 1 unit each for clarity. Solid traces represent theoretical fits of the experimental data obtained using a typical three-level model expression. The corresponding $g^2(0)$ values are 0.48 and 0.43, corresponding to single photon generation probabilities of 52% and 57% above saturation.

Figure 3.9. Plot of the power-dependent emission lifetime, τ_1 , and metastable state lifetime, τ_2 , (obtained by fitting the data in **Fig. 3.8**) versus excitation power for the emitters with ZPLs at **(a)** 633 nm and **(b)** 714 nm, respectively. The emission lifetime, τ^{0}_{1} , and metastable state, τ^{0}_{2} , were deduced by extrapolating the data to zero excitation power.

Figure 3.10. Room (295 K) and low (14 K) temperature spectra of representative emitters from (a) Group 1 (dashed and solid red traces), and (b) Group 2 (dashed and solid blue traces), respectively. At 14 K the line widths approach 3.87 and 1.17 meV.

Figure 4.1. (a) Optical microscope image of bulk hBN. The scale bar indicates 100 μ m. (b) Raman scattering spectrum obtained with a 633 nm He-Ne laser showing a peak at 1365 cm⁻¹ with a FWHM of 8.2 cm⁻¹.

Figure 4.2. Optical microscope images of bulk hBN samples with (a) a high density of dislocation defects (Bulk1), and (b) a low density of dislocation defects (Bulk2). Numerous planar stacking faults can be clearly seen in sample Bulk1. The scale bars indicate 100 μ m. (c) Raman scattering spectra obtained with a 633 nm He-Ne laser showing a peak at 1365 cm⁻¹ with a FWHM of 8.2 cm⁻¹ for each sample. (d) NEXAFS spectra around the B K-edge spectral region. The inset details a spectral region in which sample Bulk1 shows higher intensity peaks compared to Bulk2 (i.e., a higher concentration of defects relative to Bulk2).

Figure 4.3. Cathodoluminescence spectra acquired at 295 K (red trace) and 77 K (blue trace) from sample (a) Bulk1 and (b) Bulk2. The inset is a schematic illustration of the CL setup.

Figure 4.4. Optical characterization performed with a 532 nm continuous wave (CW) laser and a 568 nm long pass filter in the collection pathway. (a) A typical confocal map of bulk hBN showing a number of isolated emission centers and ensembles of these centers. The scale bar indicates $10 \ \mu\text{m}$. (b) A room-temperature photoluminescence spectrum of the isolated emission circled in the PL confocal map. The solid red and dotted grey traces represent emitter and background spectra, respectively. The emitter spectrum reveals a pair of peaks at 618 nm and 629 nm that are potentially the zero-phonon lines of the defect transition. (c) An antibunching curve recorded from the defect center in (b) showing a dip of ~ 0.35, proving the single photon emission nature of the defect. The bin size in (c) is 128 ps.

Figure 4.5. Normalized excitation (red trace) and emission (blue trace) polarization plot of defect center similar to that in **Fig. 4.6.** of the main text. The excitation source was a CW 300 μ W, 675 nm laser.

Figure 4.6. (a) A typical confocal map showing isolated emission centers and ensembles of emitters. The scale bar indicates 10 µm. (b) A room-temperature PL

spectrum of the isolated emission that is circled in the PL confocal map, revealing a broad emission band at ~ 770 – 900 nm. The solid red and dotted grey traces represent emitter and background spectra, respectively. (c) An antibunching curve recorded by continuous wave excitation of the defect center in (b) showing a dip of ~0.37, proving the quantum nature of the defect. The inset shows a similar antibunching curve obtained by pulsed excitation. (d) Time-resolved fluorescence measurement of the defect center in (b) revealing a very short radiative lifetime of ~ 1.0 ns. All measurements were done using a 675 nm CW laser at room temperature, with a 855 ± 110 nm bandpass filter. Pulsed $g^2(\tau)$ and lifetime measurements (d) were conducted using a 675 nm laser with a pulse width of 45 ps, a power of 200 μ W, and repetition rate of 80 MHz. The bin size in (b) and (d) is 128 ps.

Figure 4.7. (a) Long time-scale second-order autocorrelation function (recorded up to 0.1 s) reveals at least three possible metastable states of the defect center characterized in **Fig. 4.3**. The inset illustrates the possible excited electronic configuration of the defect center, including the existence of three metastable states. Temporal fluorescence intensity fluctuations at (b) 150 μ W, (d) 600 μ W, and (f) 2000 μ W and the corresponding histograms at (c) 150 μ W, (e) 600 μ W, and (g) 2000 μ W. The black traces in (c), (e), and (g) are corresponding simulated Poisson distributions, shown for comparison. The time-bin size in (b), (d) and (f) is 50 ms.

Figure 4.8. Histogram of fluorescence OFF (blue trace) and ON (red trace) time (%) for the emitter presented in Fig. 4.3 of the main text. A cut-off threshold of 10 % of maximum fluorescence intensity was used to define the OFF state and generate the histogram.

Figure 5.1. (a) Cryogenic confocal PL setup. HBT: Hanbury-Brown and Twiss; BS: beamsplitter; FT: band-pass or long-pass filters; $\lambda/2$: half-wave plate; Pol: linear polarizer. (b) Confocal PL map recorded with 700-nm laser excitation at 300 μ W. The bright spot corresponds to a single emitter. The measurement was acquired at 8 K. (c) Normalized PL spectrum taken from the same emitter at 8 K (blue trace) and 298 K (red trace) with a 300g/mm grating. The green-highlighted box indicates the collected spectral range for the PLE experiment in Fig. 5.3. The inset shows a higher resolution spectrum taken from the same emitter (with a 1800g/mm grating). (d) Second-order autocorrelation function (black open circles) acquired for the emitter using a 700 nm laser at 100 μ W power as the excitation source, acquired for 5 minutes. The measurement was conducted at 8 K. The red solid line is the fitting for the g⁽²⁾(0) function using a three-level model convoluted by a Gaussian jitter response (see main text). The g⁽²⁾(0) value of 0.16 \pm 0.01, without any background correction, indicates that the emission is from a single emitter. The standard deviation was based on the standard deviation taken from the long delay region. A band-pass filter was used in the measurements of confocal PL in (b) and the photon second-order autocorrelation function (d) to minimize the background PL contribution.

Figure 5.2. (a) Spectra showing maximum (red trace) and minimum (blue trace) emission polarization from the emitter taken with the use of a linear polarizer. The data was taken using an excitation laser power of 300 μ W with a 5 s acquisition time. The visibility was determined to be unity. (b) Power-dependent fluorescence saturation curve (red open circles). The fit (solid red line) produces values of I_{max} and P_{sat} of 1.3 Mcounts/sec and 1.6 mW, respectively. The measurement was acquired with a band pass filter (760 \pm 12) nm. All the measurements were conducted at room temperature.

Figure 5.3. (a) Simplified diagram of the hBN emitter where the excited state can be accessed via either off-resonance or on-resonance excitation, with the former pathway on the left, and the latter pathway on the right. Black and grey arrows indicate excitation towards the higher vibronic states, followed by vibronic relaxation towards the excited ground state. The green arrow indicates onresonance excitation, followed by spontaneous emission denoted by the wavy red arrow in both pathways. **(b)** Resonance photoluminescence excitation measurements on the single emitter with a ZPL peak at 766.186 nm. The excitation power used was 150 nW. Only photons from the PSB were collected using a long pass filter. The experimental data is plotted as the red trace. Five repetitive scans were averaged out to get the final data. The data was fit with either a Gaussian function (black solid line). The measurement was done at 8 K. **(c)** Additional survey PLE scans showing multiple local maxima with FWHM below 2 GHz. The grey arrows show representative spectral features that are asymmetrical. **(d)** Time-resolved PL measurements (red open circles) of the same single emitter measured at room temperature. A single-exponential fit gives rise to a lifetime of 3.6 ns for the emitter's excited state. The measurement was done with a 675 nm pulsed laser (100 μ W, 10 MHz repetition rate, 100 ps pulse width).

Figure 5.4. Optical characterization of another defect center. (a) High- and lowresolution (inset) PL spectra taken from the emitter by off-resonant excitation at 700-nm with 300 μ W laser power. (b) Five repeated scans over 60 GHz range showing some complete optical resonance features as well as some asymmetrical features. (c) On-resonant excitation with the laser fixed at 787.592 nm (red solid line) and 2-nm detuned from the on-resonance excitation wavelength (black solid line). The calculated $\tau_{ON}/\tau_{OFF} = 0.09$ indicates that the emitter is mostly in unexcited states.

Figure 5.5. (a) PL intensity vs time for on-resonance (red line) and 2 nm detuned (black) excitation of the same emitter. The blue dash line represents the cut-off threshold (1800 count/sec) for calculating τ_{on} and τ_{off} . The τ_{on} / τ_{off} ratio was calculated to be 0.47. The data are vertically shifted for clarity. (b) Histogram of on-resonance time extracted from an on-resonance trace of (a). The calculated average spectral diffusion time, $\tau_{avg spec diff} = 102 \pm 65$ ms. (c) Confocal PL map with the laser staying on-resonance (left panel) and 2 nm detuned (right panel) from the resonance. The measurements in (a) and (b) were carried out at the excitation power of 150 nW. (d) On-resonance photon second-order correlation function (black open circles) acquired for the emitter at 1 μ W excitation power for three hours. The red solid line is the fitting for the $g^{(2)}_{meas}(0)$ function using the Gaussian-convoluted three-level model, resulting in an antibunching dip value of 0.11 ± 0.04 . The standard deviation was based on the standard deviation taken from the long delay time region. It must be noted that no smoothing procedure was implemented for this measurement. All the measurements were conducted at 8 K.

Figure 6.1. (a) Optical image of exfoliated hBN flakes. *(b)* Table of the investigated samples comprised of a reference sample, four samples that were implanted by ions, one processed by a laser beam and one by an electron beam.

Figure 6.2. (a-d) PL spectra from hBN flakes implanted with B, BN, O and Si ions. The insets are second-order autocorrelation functions, $g^{(2)}(\tau)$, recorded from each sample, demonstrating the emitters are single photon sources. A spectrum from a reference sample and a corresponding $g^{(2)}(\tau)$ function are shown in the (**Fig. 6.8**).

Figure 6.3. (a) A table comparing the number of formed emitters found in each ion-implanted sample and a reference sample that was only subjected to annealing. (b, c) Examples of stability curves from a single emitter in an ion implanted flake (b) and in a reference flake (c). Blinking followed by bleaching was much more common in the reference sample than in the implanted samples.

Figure 6.4. Confocal maps from **(a-c)** B, **(d-f)** BN, **(g-i)** O and **(j-l)** Si implanted hBN flakes, demonstrating unambiguously that the emitters are always localized at flake edges. Large bright features seen away from flake edges, as in map **(i)**, do not exhibit photon antibunching, and do not possess the spectral characteristics of the single photon emitters discussed in this study.

Figure 6.5. (a-d) Example of excitation (red circles) and emission (blue squares) polarization plots of single emitters from each of the implanted samples. All the emitters exhibit dipole like behavior in both excitation and emission.

Figure 6.6. Fabrication of emitters using laser processing. (a) Confocal map of the hBN flakes. The white circle indicates the presence of the location of a single photon emitter. (b) PL spectrum recorded from the emitter. Inset: $g^{(2)}(\tau)$ curve confirming it is indeed a single photon emitter. (c) excitation and emission polarization curves (red circles and blue squares, respectively,) recorded from this emitter.

Figure 6.7. Fabrication of emitters by electron beam irradiation. Confocal map of the same flake before (a) and after (b) electron beam irradiation. The energy of the beam is 15 keV. (c) Spectra recorded from a particular location before (blue curve) and after (red curve) irradiation. Inset, a $g^{(2)}(\tau)$ curve confirming the formed defect is a single photon source. (d) Excitation and emission polarization from the same defect. The sample was not annealed after electron irradiation.

Figure 7.1. Hexagonal boron nitride flakes and their transfer process onto plasmonic lattice substrates. (a) Schematic illustration of the wet process used to transfer a selected hBN flake with an emitter of choice (exemplified by the red dot) from a thermal silicon oxide substrate onto a plasmonic NP array using PMMA as the carrier. (b) SEM image of the mechanically exfoliated hBN flake positioned atop of a silver plasmonic lattice on silica and (c) optical image of the same flake on the plasmonic lattice. (d) FDTD simulation of the lateral (in-plane) electric field intensity distribution $|E|^2$ of a 400 nm-spacing silver plasmonic lattice structure.

Figure 7.2. Finite-difference time-domain simulation of the vertical (cross-sectional) electric field intensity distribution |E| of a silver nanoparticle (NP) array with 400-nm spacing.

Figure 7.3. Confocal PL map (a) and its corresponding larger field-of-view SEM image (b) shown in main text **Fig. 6.2a**. A good spatial correlation between the confocal map and the SEM image can be observed. The SEM image unarguably shows that the flakes are positioned atop the gold plasmonic NP array.

Figure 7.4. Coupling between a quantum emitter in a tape exfoliated hBN flake and a gold NP array on silica. (a) PL confocal map of a flake containing a single photon emitter (red circled). Inset, SEM image of part of the flake on top of the gold plasmonic lattice. The scale bar represents 2 µm. (b) PL spectra of the pristine (red trace) and coupled (blue trace) single photon emitter, and a transmission spectrum of the plasmonic lattice (green trace) with the plasmonic resonance at 640 nm. (c) Second-order autocorrelation functions obtained from the pristine (red circles) and coupled (blue open squares) system. In both cases, the dip at zero delay time falling well below 0.5 implies single photon emission. Background correction was employed to correct the antibunching curves due to high PL background coming from the hBN flake. The $g^{(2)}(0)$ values for emission from pristine and coupled emitters are at 0.02 and 0.04, respectively. Red and blue solid lines are fits obtained using a three-level model. (d) Time-resolved PL measurements from the pristine (red open circles) and coupled (blue open squares) systems. Red and blue solid lines are double exponential fits. A 532 nm continuous-wave laser was used in (a), (b) and (c). A 512 nm pulsed laser with a repetition rate of 10 MHz and 100 ps pulse width was used in (d).

Figure 7.5. A full-range transmission spectrum of a gold array in Fig. 7.4. The solid line implies the 532 nm excitation laser used in this study. There is a negligible pump absorption by the plasmonic array according to the spectrum.

Figure 7.6. Confocal PL maps of before and after the solvent-exfoliated flakes being transferred onto the plasmonic NP array. The two maps show a good agreement on the spatial location and relative orientation of the flakes to one another, confirming that the same flakes were examined.

Figure 7.7. Coupling between a quantum emitter in a solvent exfoliated hBN flake and a gold NP array on a silica substrate. (a) PL spectra of a pristine (red trace) and coupled (blue trace) single photon emitter, and a transmission spectrum of the gold lattice (green trace). Inset: SEM image of the hBN flakes ontop the gold NP array. (b) Second-order autocorrelation functions obtained from the pristine (red open circles) and coupled (blue open squares) systems. The $g^{(2)}(0)$ values for emission from pristine and coupled emitters are 0.23 and 0.47, respectively. In both cases, the dip at zero delay time falling well below 0.5 implies single photon emission. Red and blue solid lines are fits obtained using a three-level model. (c) Time-resolved PL measurements from the pristine (red open circles) and coupled (blue open squares) systems. Red and blue solid lines are double exponential fits. (d) Fluorescence saturation curves obtained from the pristine (red open circles) and coupled (blue open squares) systems. Red and blue solid lines are fits obtained using equation 2. A 532 nm continuous-wave laser was used in (a), (b) and (d). A 512 nm pulsed laser with a repetition rate of 10 MHz and 100 ps pulse width was used in (c).

Figure 7.8. Coupling between a quantum emitter in a solvent exfoliated hBN flake and a silver NP array on a silica substrate. (a) PL spectra of a pristine (red trace) and coupled (blue trace) single photon emitter, and a transmission spectrum of the silver lattice (green trace). (b) Second-order autocorrelation functions obtained from the pristine (red open circles) and coupled (blue open squares) systems. In both cases, the dip at zero delay time falling well below 0.5 implies single photon emission. Red and blue solid lines are fits obtained using a three-level model. The $g^{(2)}(0)$ values for emission from pristine and coupled emitters are 0.06 and 0.29, respectively. (c) Time-resolved PL measurements from the pristine (red open circles) and coupled (blue open squares) systems. Red and blue solid lines are double exponential fits. (d) Fluorescence saturation curves for obtained from the pristine (red open circles) and coupled (blue open squares) systems. Red and blue solid lines are fits obtained using equation 2. A 532 nm continuous-wave laser was used in (a), (b) and (d). A 512 nm pulsed laser with a repetition rate of 10 MHz and 100 ps pulse width was used in (c).

Figure 8.1. Characterization of the multilayers. (a) Optical image of annealed WS_2 multilayers. The scale bar is 10 µm. No visible difference could be seen before and after annealing. (b) Raman spectra of a pristine monolayer (red), pristine multilayer (green), and multilayers that were annealed in argon at 550°C (blue). The grey and yellow highlighted boxes denote E_{2g} and 2LA mode, and A_{1g} vibration mode of WS_2 . (c) TEM image of an annealed flake and (d) the corresponding selected area electron diffraction taken from (c). The diffraction pattern indicates the cubic phase of WO_3 . (e-g) XPS spectra of WS_2 annealed at 550°C in an Argon atmosphere, showing spectral regions that contain the O_{1s} , S_{2p} and W_{4f} peaks, respectively. In (c) the presence of a WO_x phase is clearly observed.

Figure 8.2. Bright-field optical images of WS_2 flakes after being annealed at 550°C in argon for 30 min. The scale bars are 10 μ m. The WS_2 flakes have lateral size of ~0.3 – 3 μ m and thickness of ~5 – 300 nm.

Figure 8.3. Single photon emission from annealed multilayers. (a) A typical confocal photoluminescence map showing several bright spots corresponding to localized defects. (b) Photoluminescence spectra taken from three bright spots. A spectrum from monolayer WS_2 is plotted for comparison (c) Second-order autocorrelation measurement obtained from the three emitters. The curves are offset vertically for clarity. (d) Time-resolved photoluminescence measurement recorded from the three emitters, yielding excited state lifetimes of 3.5 ns, 4.6 ns, and 4.4 ns, respectively for emitters S1, S2 and S3. The pump power used in (a, b, c) was 300 μ W at 532 nm while the pulsed measurement was done using a 512 nm laser (10 MHz, 50 μ W).

Figure 8.4. Fluorescence saturation and polarization of emitter S1. (a) Fluorescence intensity as a function of pump power. The red open circles and grey open triangles denote background-corrected fluorescence profile of emitter S1 and background fluorescence taken at an area adjacent to the emitter (in **Fig. 8.3**). The solid lines are corresponding fitted curves. The saturated intensity is 347,000 cps with the saturated pump at 1.9 mW. (b) Excitation (red open circles) and emission (blue open squares) measurement for emitter S1. Solid lines are corresponding fits. (c) Fluorescence stability measurement over 10 minutes at an excitation power of 1mW. No bleaching or blinking could be seen from the measurement. Measurements taken in (**a-c**) were done with CW 532 nm laser.

Figure 8.5. Additional polarization data taken from three different single photon emitters from the annealed WS₂ sample. Red open circles and blue open squares denote excitation and emission measurement, respectively. Solid lines are corresponding fits. Measurements were done with CW 532 nm laser.

Figure 8.6. (a) Antibunching curves as a function of pump power. Solid lines are fitted profile using the standard three-level model. (b) Emission (τ_1) and metastable (τ_2) lifetime plotted as a function of excitation power. By applying linear fitting and extrapolating the fits to vanishing excitation power, emission (τ_1) and metastable (τ_2) lifetime are calculated to be 4.5 ns and 9.3 ns, respectively. (c) Proposed three-level diagram of the emitters with a ground state, an excited state, and a metastable state. Black, red and grey arrows represent excitation, emission, and non-radiative transitions.

List of Tables

 Table 3.1. Additional metastable states associated with the investigated emitters.

Abbreviations

- 0D zero dimensional
- 1D one dimensional
- 2D-two dimensional
- 3D three dimensional
- APD avalanche photodiode
- $\mathrm{CL}-\mathrm{cathodoluminescence}$
- CVD chemical vapor deposition
- CW continuous wavelength
- EPR electron paramagnetic resonance
- FIB focused ion beam
- FWHM full width at half maximum
- hBN hexagonal boron nitride
- HBT Hanbury Brown and Twiss
- IRF instrument response function
- NIR near infra-red
- PL photoluminescence
- PSB phonon sideband
- ODMR optically detected magnetic resonance
- QDs quantum dots
- QE quantum efficiency
- QIP quantum information processing

- QKD quantum key distribution
- SEM scanning electron microscope
- SPS single photon source
- SRIM stopping and range of ions in matter
- $WS_2-tungsten \ disulfide$
- ZPL zero phonon line

Abstract

Realization of quantum technologies demands successful assembly of crucial building blocks. Quantum light sources, lying at the heart of this architecture, have attracted a great deal of research focus during the last several decades. Optically active defect-based centers in wide bandgap materials such as diamond and silicon carbide have been proven to be excellent candidates due to their high brightness and photostability. Integration of quantum emitters on an on-chip integrated circuit, however, favors low dimensionality of the host materials. Single photon sources embedded in two-dimensional lattices are, therefore, highly desired. In this thesis, we introduce a class of novel quantum systems hosted in hexagonal boron nitride (hBN) – a wide bandgap semiconductor in the two-dimensional (2D) limit. First, we demonstrate experimentally that the quantum systems possess a record high single photon count rate, exceeding 4 MHz at room temperature. Polarization and time-resolved spectroscopy reveal their full emission polarization and short excited state lifetime (~ 3 ns). Besides, the emitters from this class of quantum system also show extremely high stability under high excitation at ambient conditions. By employing spin-resolved density functional theory (DFT) calculation, we suggest that the defect center is an antisite nitrogen vacancy (N_BV_N). A multicolor phenomenon where there is a wide distribution of zerophonon lines (ZPL) from different emitters is also observed and can be attributed to strain field in the hBN lattice thanks to DFT calculation. Additionally, we demonstrate the ability to create the emitters by means of thermal treatment or electron beam induced etching. Under harsh environments, strikingly, most of the emitters survive and preserve their quantum properties. Resonant excitation spectroscopy reveals a linewidth of ~6 GHz, and a high single photon purity confirmed from an emitter by on-resonance antibunching measurements. Studies on bulk hBN crystals reveal that the emitters tend to locate at dislocations or stacking faults in the crystals. We also demonstrate ion implantation and laser ablation as means of increasing formation yield of the emitters in mechanically exfoliated hBN flakes. Next, the coupling of quantum emitters in hBN to plasmonic particles arrays is demonstrated, showing several times Purcell enhancement factor. Lastly, we show that another 2D material - tungsten disulfide (WS_2) – when being oxidized also hosts quantum emitters at room temperature. This observation, therefore, opens a new avenue for studying quantum emitters embedded in other 2D materials.